Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
09/762,424	HAYASHI, MORIHIKO	IHIKO	
Examiner	Art Unit		
Kevin Mew	2616		

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SEARCHED						
Class	Subclass	Date	Examiner			
370	444	11/5/2007	KM			
370	459	11/5/2007	КМ			
Updated	Updated					

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
(see S		11/5/2007	KM		
History	Printout)			

(INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
370/328-330, 341, 347-348 370/431-432 370/437, 441-443, 458, 461-462 (Text search only) Updated Search	11/5/2007	KM		
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